



**RESPONSE UNDER 37 C.F.R. § 1.116
EXPEDITED PROCEDURE REQUESTED
EXAMINING GROUP 2863**

PATENT
Customer No. 22,852
Attorney Docket No. 3180.0269-00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Chie IWASA

Application No.: 09/708,490

Filed: November 9, 2000

For: SEMICONDUCTOR TESTING
METHOD AND SEMICONDUCTOR
TESTING APPARATUS FOR
SEMICONDUCTOR DEVICES, AND
PROGRAM FOR EXECUTING
SEMICONDUCTOR TESTING
METHOD

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)
) **Group Art Unit: 2863**
)
) **Examiner: Lau, Tung S.**
)
)
) **Mail Stop AF**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

AMENDMENT AFTER FINAL

In reply to the Final Office Action mailed September 5, 2003, and pursuant to 37 C.F.R. § 1.116, Applicant proposes that this application be amended as follows:

Amendments to the Claims are reflected in the listing of claims as beginning on page 2 of this paper.

Remarks/Arguments follow the amendment sections beginning on page 15 of this paper.

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